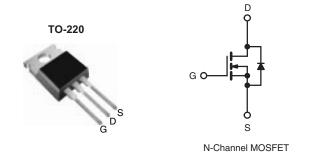


COMPLIANT

Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	10	100			
$R_{DS(on)}\left(\Omega\right)$	V _{GS} = 10 V	0.27			
Q _g (Max.) (nC)	10	16			
Q _{gs} (nC)	4.	4.4			
Q _{gd} (nC)	7.7				
Configuration	Sin	Single			



FEATURES

- Dynamic dV/dt Rating
- · Repetitive Avalanche Rated
- 175 °C Operating Temperature
- Fast Switching
- · Ease of Paralleling
- Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION		
Package	TO-220	
Lead (Pb)-free	IRF520PbF	
Lead (Fb)-liee	SiHF520-E3	
SnPb	IRF520	
SHED	SiHF520	

ABSOLUTE MAXIMUM RATINGS T	_C = 25 °C, unless otherw	rise noted			
PARAMETER	SYMBOL	LIMIT	UNIT		
Drain-Source Voltage		V_{DS}	100		
Gate-Source Voltage	V_{GS}	± 20	- V		
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		9.2	A	
	V_{GS} at 10 V $T_C = 100 ^{\circ}C$	I _D	6.5		
Pulsed Drain Current ^a	I _{DM}	37	1		
Linear Derating Factor		0.40	W/°C		
Single Pulse Avalanche Energy ^b		E _{AS}	200	mJ	
Repetitive Avalanche Current ^a	I _{AR}	9.2	Α		
Repetitive Avalanche Energy ^a	E _{AR}	6.0	mJ		
Maximum Power Dissipation	T _C = 25 °C	P _D	60	W	
Peak Diode Recovery dV/dtc	dV/dt	5.5	V/ns		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to + 175	00	
Soldering Recommendations (Peak Temperature)	for 10 s	-	300 ^d	°C	
Mounting Torque	C OO or MO corou:		10	lbf ⋅ in	
	6-32 or M3 screw		1.1	N⋅m	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. $V_{DD} = 25 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 3.5 mH, $R_G = 25 \Omega$, $I_{AS} = 9.2 \text{ A}$ (see fig. 12).
- c. $I_{SD} \le 9.2$ A, $dI/dt \le 110$ A/ μ s, $V_{DD} \le V_{DS}$, $T_J \le 175$ °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply



THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	2.5	

PARAMETER	SYMBOL	TEST	TEST CONDITIONS		TYP.	MAX.	UNIT
Static					•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference	Reference to 25 °C, I _D = 1 mA		0.13	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zana Onto Walterna Basis Omerai		V _{DS} = 100 V, V _{GS} = 0 V		-	-	25	,
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V	_{'GS} = 0 V, T _J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 5.5 A ^b	-	-	0.27	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 50 V, I _D = 5.5 A ^b		2.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$		-	360	-	pF
Output Capacitance	C _{oss}			-	150	-	
Reverse Transfer Capacitance	C _{rss}	f = 1.0	= 1.0 MHz, see fig. 5		34	-	
Total Gate Charge	Qg	$V_{GS} = 10 \text{ V}$ $I_D = 9.2 \text{ A}, V_{DS} = 80 \text{ V},$		-	-	16	
Gate-Source Charge	Q_{gs}		-	-	4.4	nC	
Gate-Drain Charge	Q_{gd}		see fig. 6 and 13 ^b	-	-	7.7	
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 50 \text{ V}, \text{ I}_D = 9.2 \text{ A},$ $R_G = 18 \ \Omega, \ R_D = 5.2 \ \Omega, \text{ see fig. } 10^b$		-	8.8	-	- ns
Rise Time	t _r			-	30	-	
Turn-Off Delay Time	t _{d(off)}			-	19	-	
Fall Time	t _f			-	20	-	
Internal Drain Inductance	L _D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s					•	
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	9.2	- A
Pulsed Diode Forward Current ^a	I _{SM}			ı	-	37	
Body Diode Voltage	V_{SD}	$T_J = 25 ^{\circ}\text{C}, \ I_S = 9.2 \text{A}, \ V_{GS} = 0 \text{V}^{\text{b}}$		-	-	1.8	V
Body Diode Reverse Recovery Time	t _{rr}	- T _J = 25 °C, I _F = 9.2 A, dl/dt = 100 A/μs ^b		-	110	260	ns
Body Diode Reverse Recovery Charge	Q _{rr}			-	0.53	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-on time is negligible (turn		n-on is dominated by L_S and L_I			L _D)

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 μs ; duty cycle \leq 2 %.



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

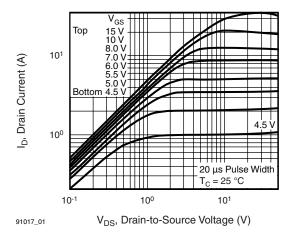


Fig. 1 - Typical Output Characteristics, T_C = 25 $^{\circ}C$

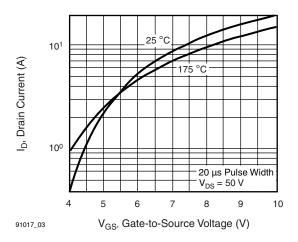


Fig. 3 - Typical Transfer Characteristics

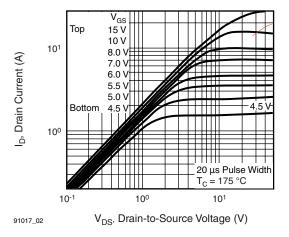


Fig. 2 - Typical Output Characteristics, T_C = 175 $^{\circ}C$

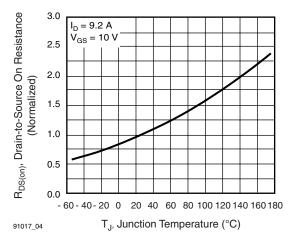
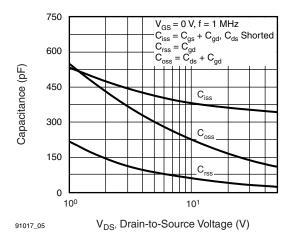


Fig. 4 - Normalized On-Resistance vs. Temperature





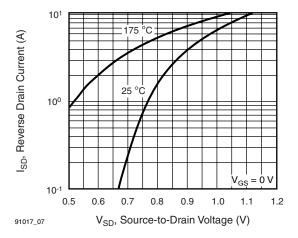
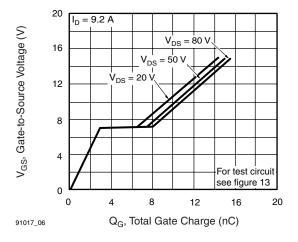


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

Fig. 7 - Typical Source-Drain Diode Forward Voltage



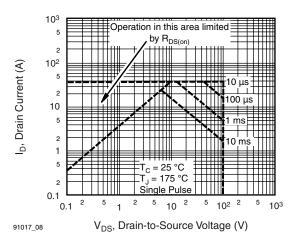
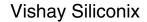


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

Fig. 8 - Maximum Safe Operating Area





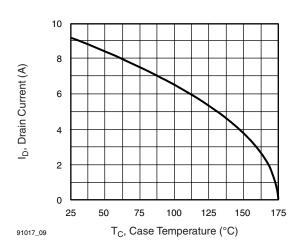


Fig. 9 - Maximum Drain Current vs. Case Temperature

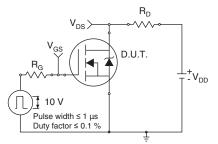


Fig. 10a - Switching Time Test Circuit

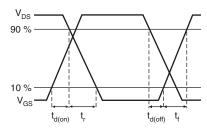


Fig. 10b - Switching Time Waveforms

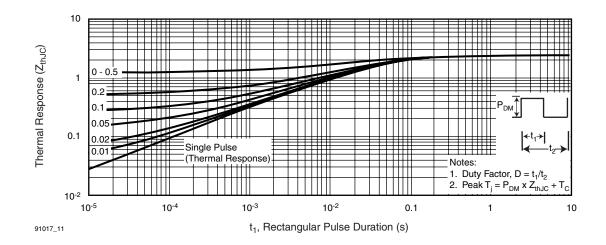


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

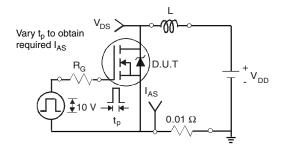


Fig. 12a - Unclamped Inductive Test Circuit

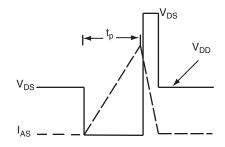


Fig. 12b - Unclamped Inductive Waveforms



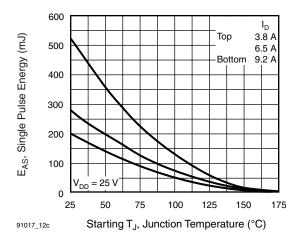


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

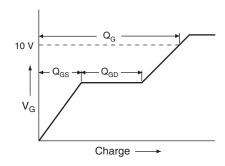


Fig. 13a - Basic Gate Charge Waveform

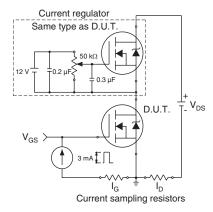
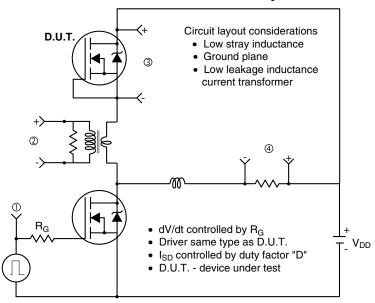
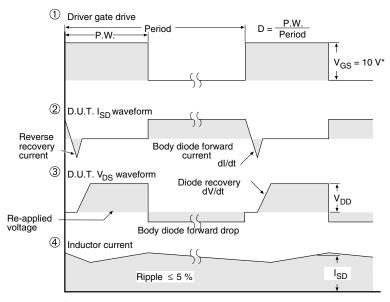


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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